

Converter architectures and conversion errors

DAT116, Nov 22 2018
larssv@chalmers.se

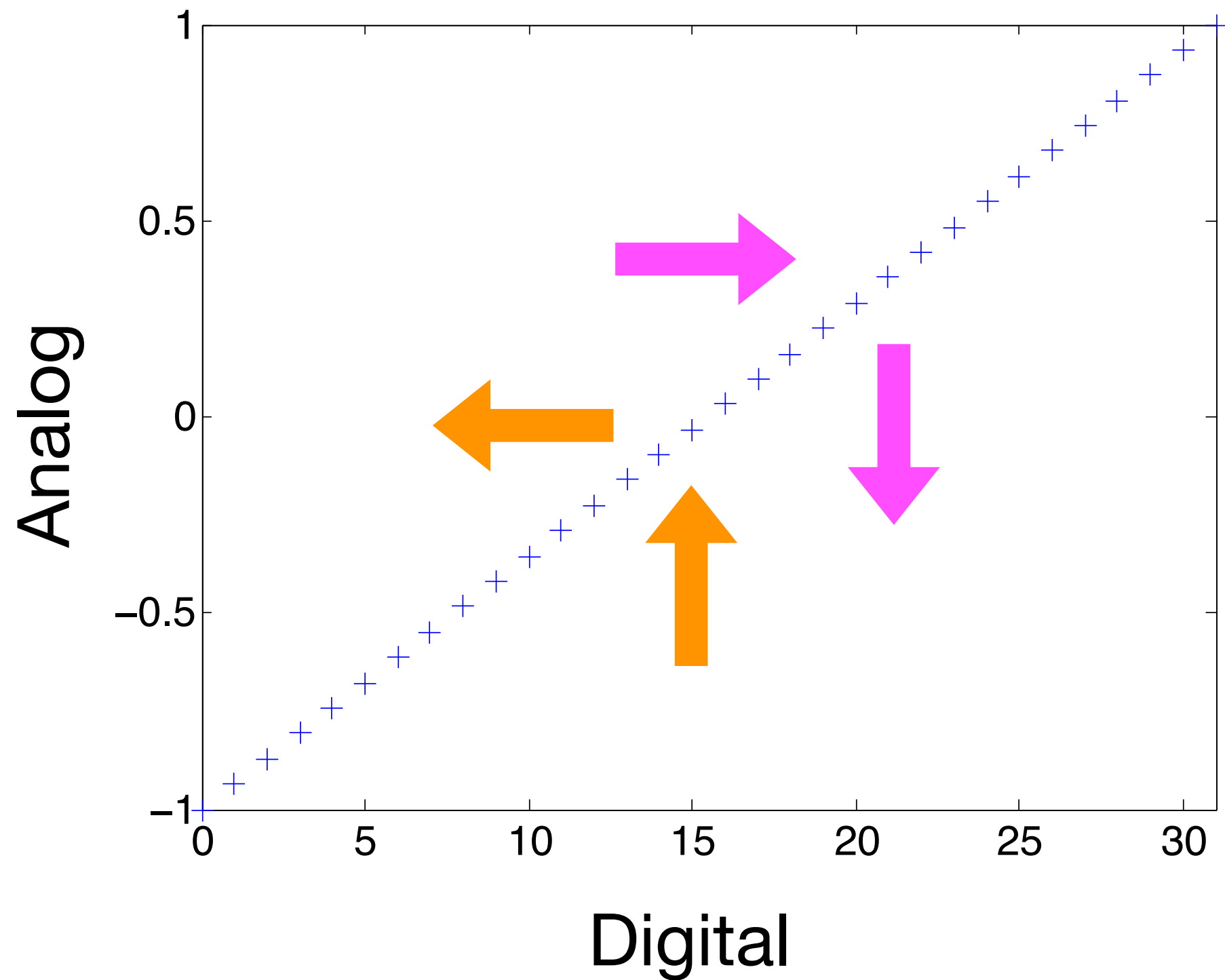
Why?

- Introduce major converter architectures
- Understand causes of quantization non-idealities
- Recognize certain common issues

What?

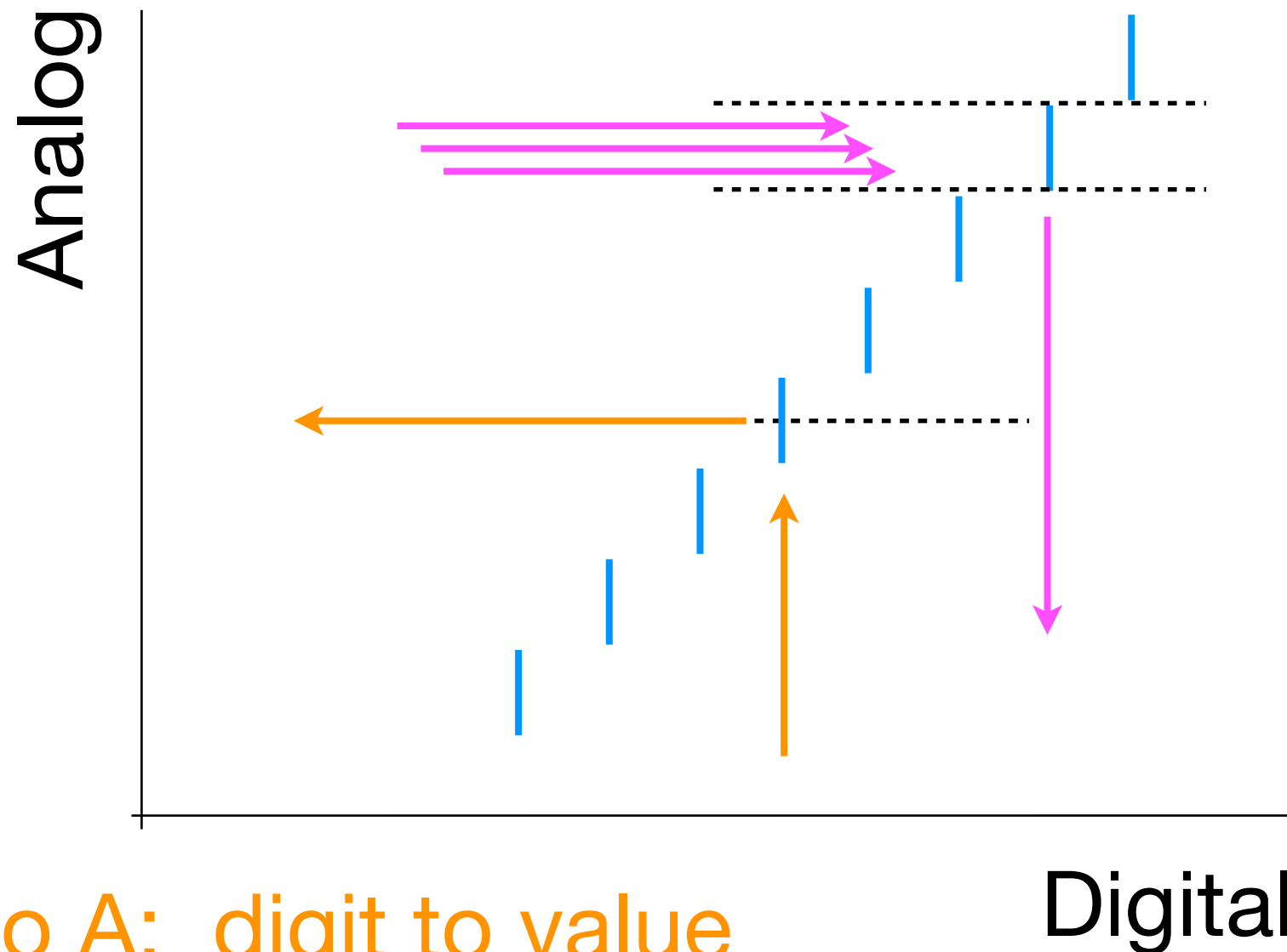
- Quantization mechanisms vs. error types
- Two main classes with different error characteristics; examples of each
 - Unary scaling
 - Binary scaling
- DACs vs ADCs; similarities and differences

ADC vs DAC



Mappings

A to D: interval to digit



Levels w/ errors:
interval edges
(ADC),
values (DAC)

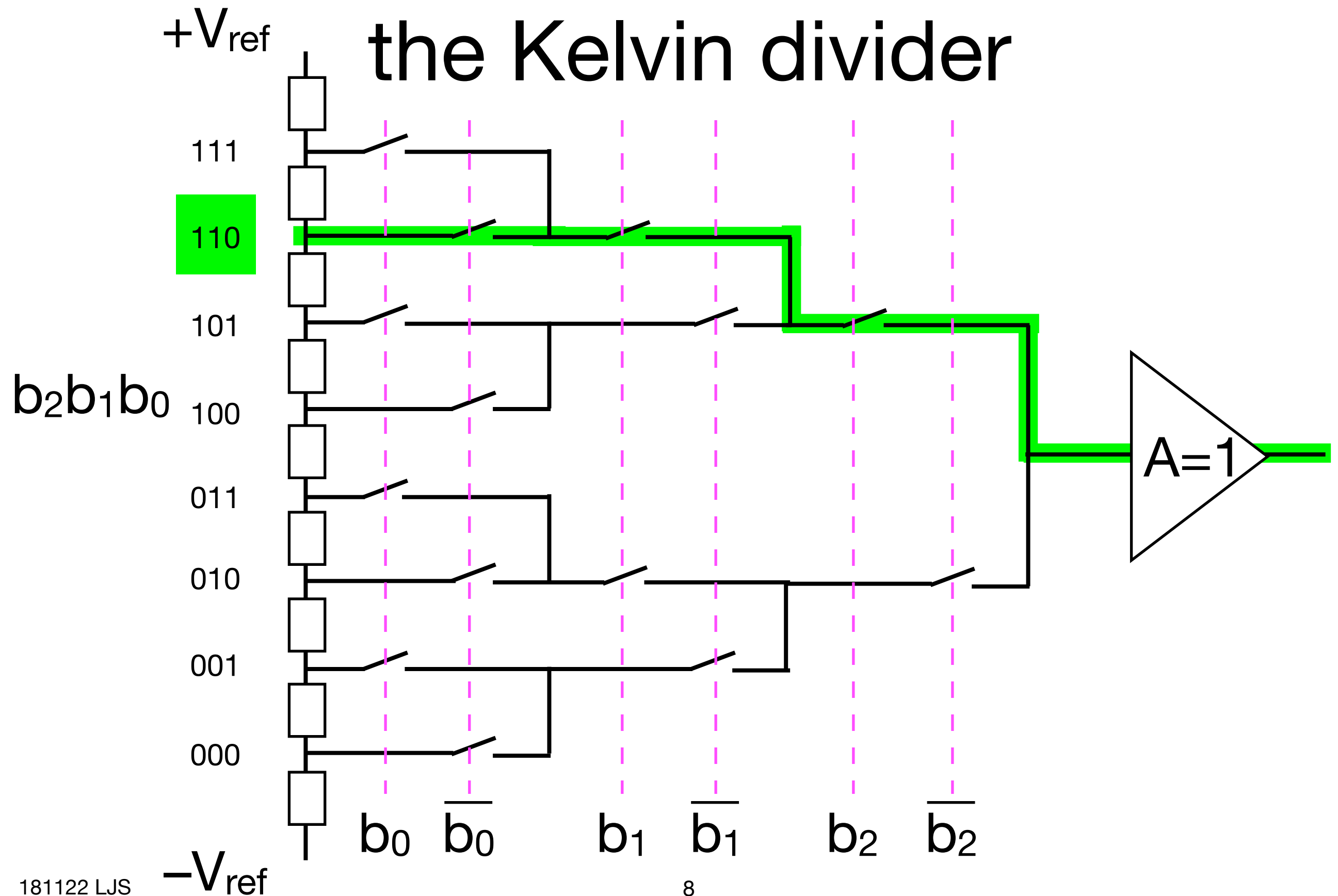
Numbers,
separations
of levels
similar

D-to-A conversion

DAC principles

- Unary scaling:
 - Kelvin divider
 - Current summer
- Binary scaling:
 - Current summer
 - Charge summer

Unary-scaling DAC: the Kelvin divider



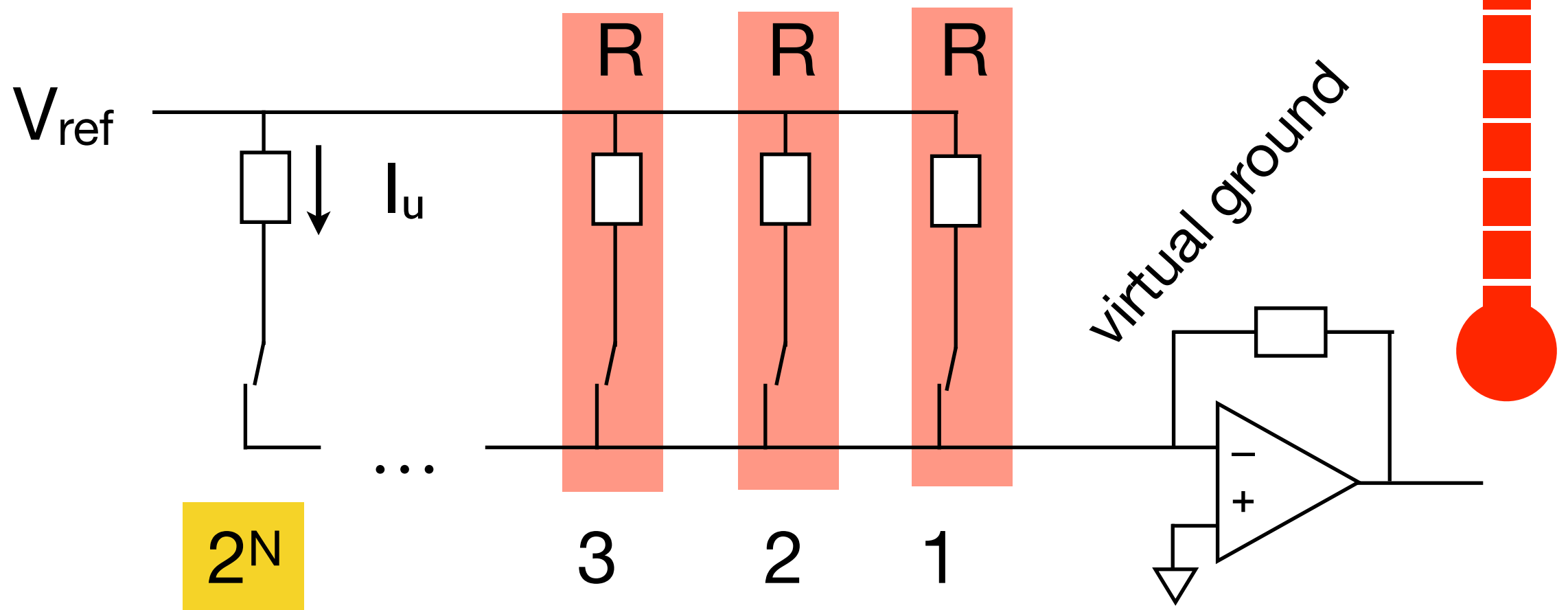
Kelvin divider performance

- Precision?
 - Resistance matching ($\sum R_i / \sum R$)
 - Large-area R_i to improve matching ...
 - ... thus large total size, so mfg gradients important
 - Larger random variations at ends of scale
- Speed?
 - Charge / discharge switch network C via R string
- Power?
 - C charging; DC current through R string
- Resolution?
 - ~6 bits

Used mostly
as part of ADCs

Current-summing DAC

- Let V_{ref} and R define a unit current I_u
- Add several of those (thermometer code)



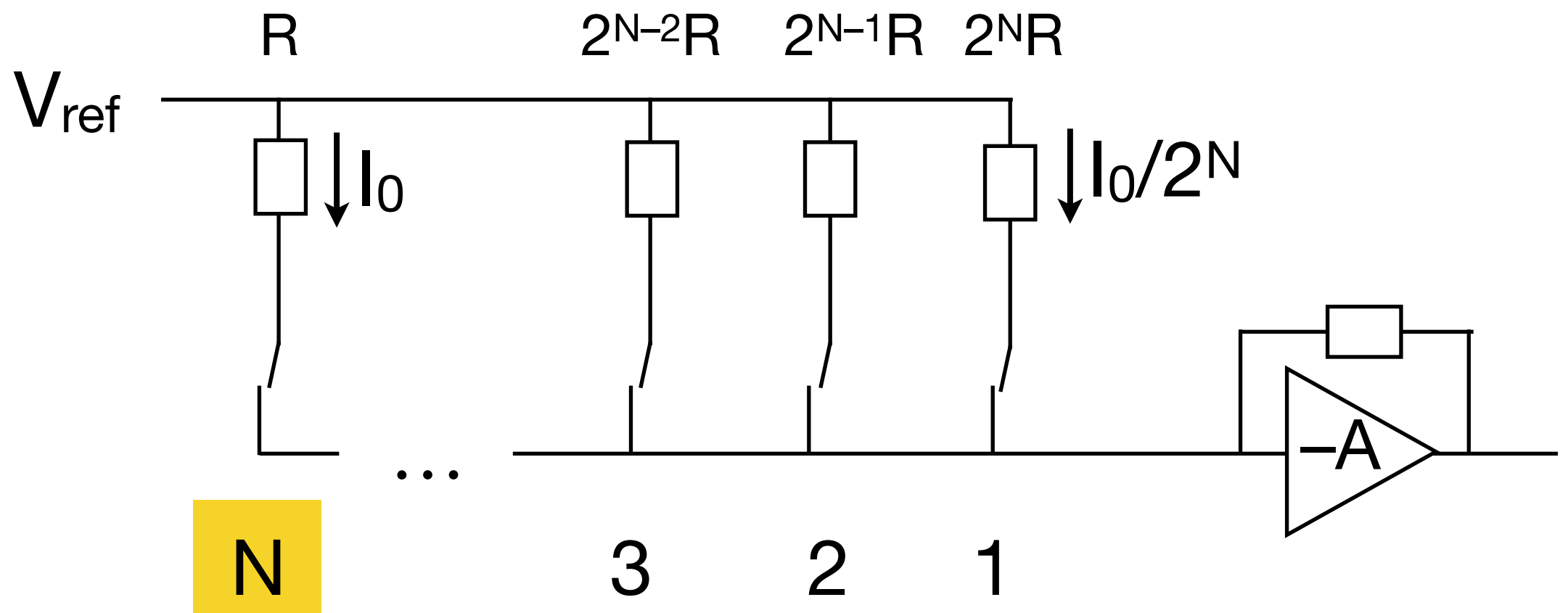
Other current generators possible

Current summer properties

- + Good matching properties!
 - All sources nominally identical (unary scaling)
- High cost
 - $\sim 2^N$ switches, current generators
- DNL limited by matching of neighbor R, switches
 - “Random” variations
- INL may be limited by manufacturing gradients
 - “Systematic” variations

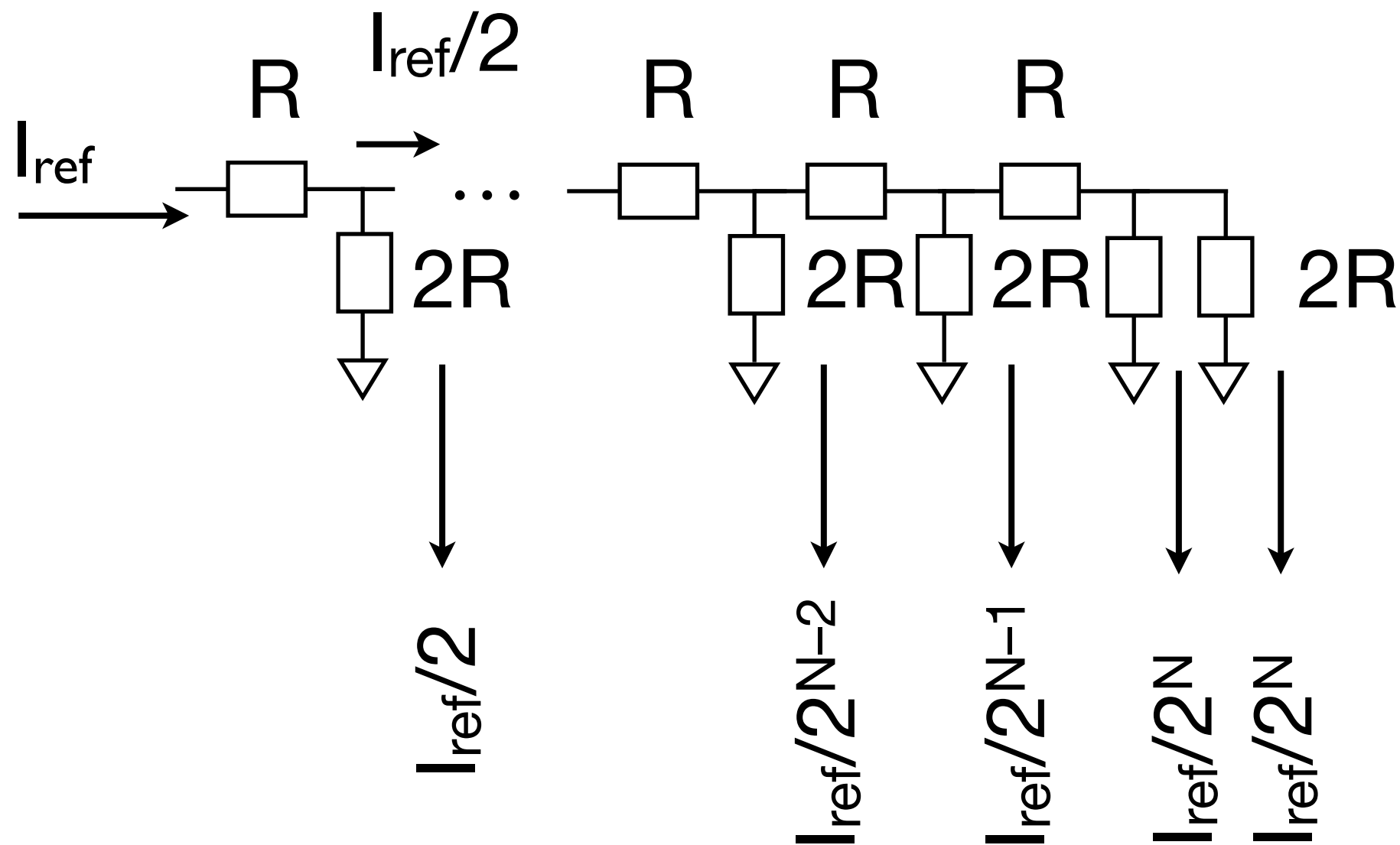
Binary scaling

- Each current 1/2 of previous one
- + ~N components! Good!
- Matching problems for large N (large R ratios)



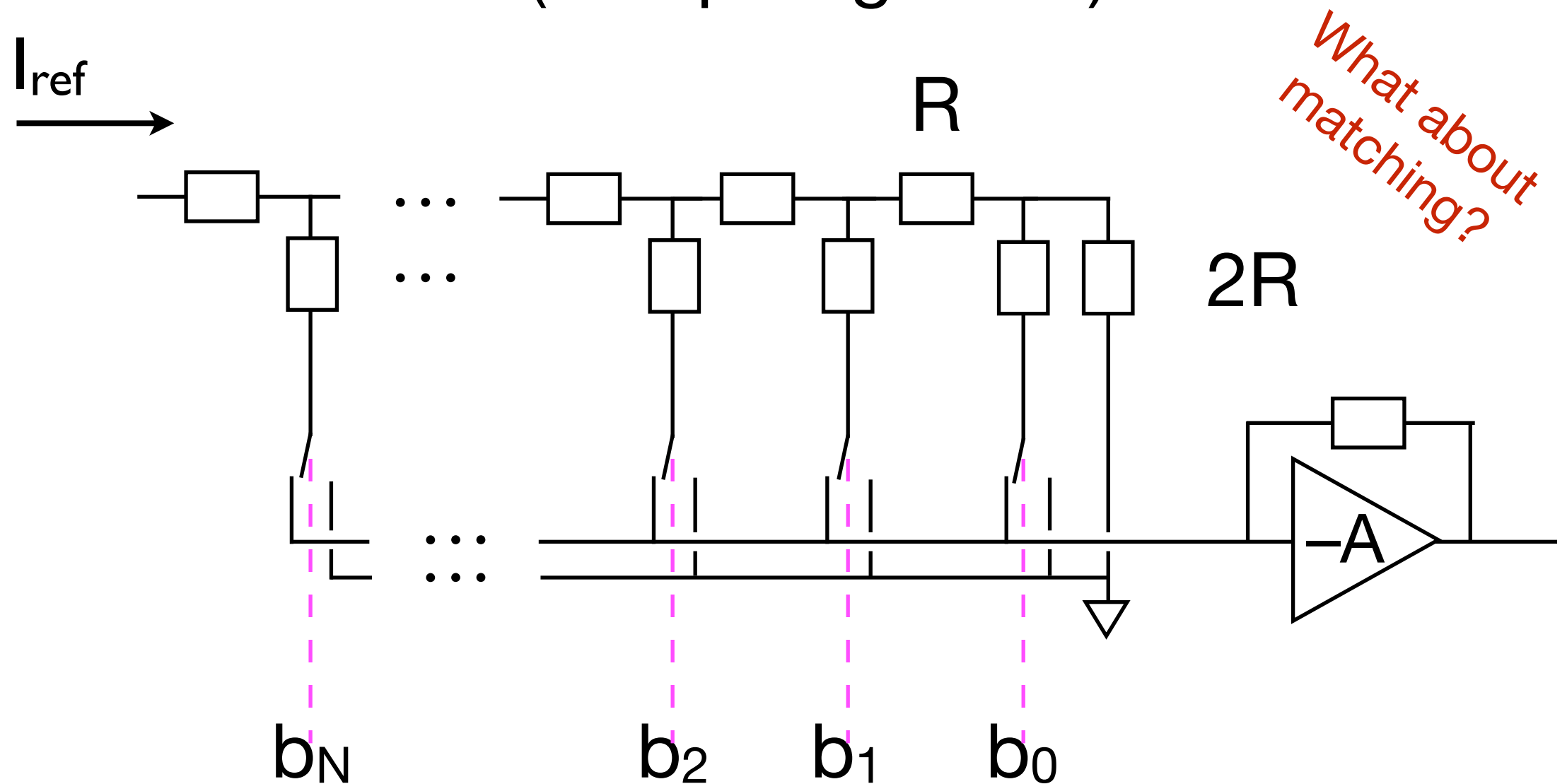
R-2R ladder

- Binary current scaling without large resistance ratios!



R-2R ladder

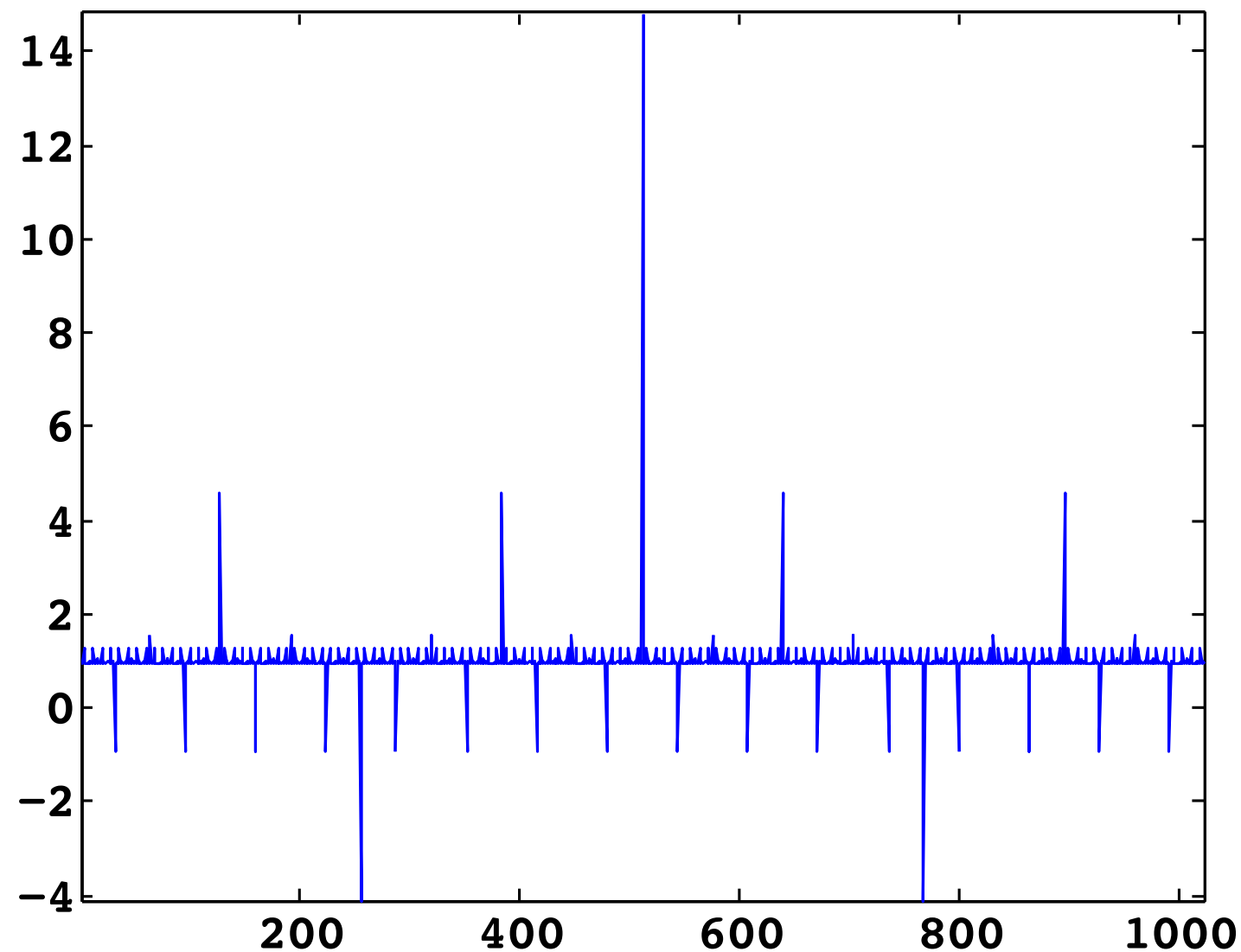
- Select some of the scaled currents; sum
- Discard rest (dump to ground)



DNL for R2R

- Random deviations from nominal R

...
011101
011110
011111
100000
100001
100010
100011
...



Typical
binary-
scaled

More in
lab

R-2R properties

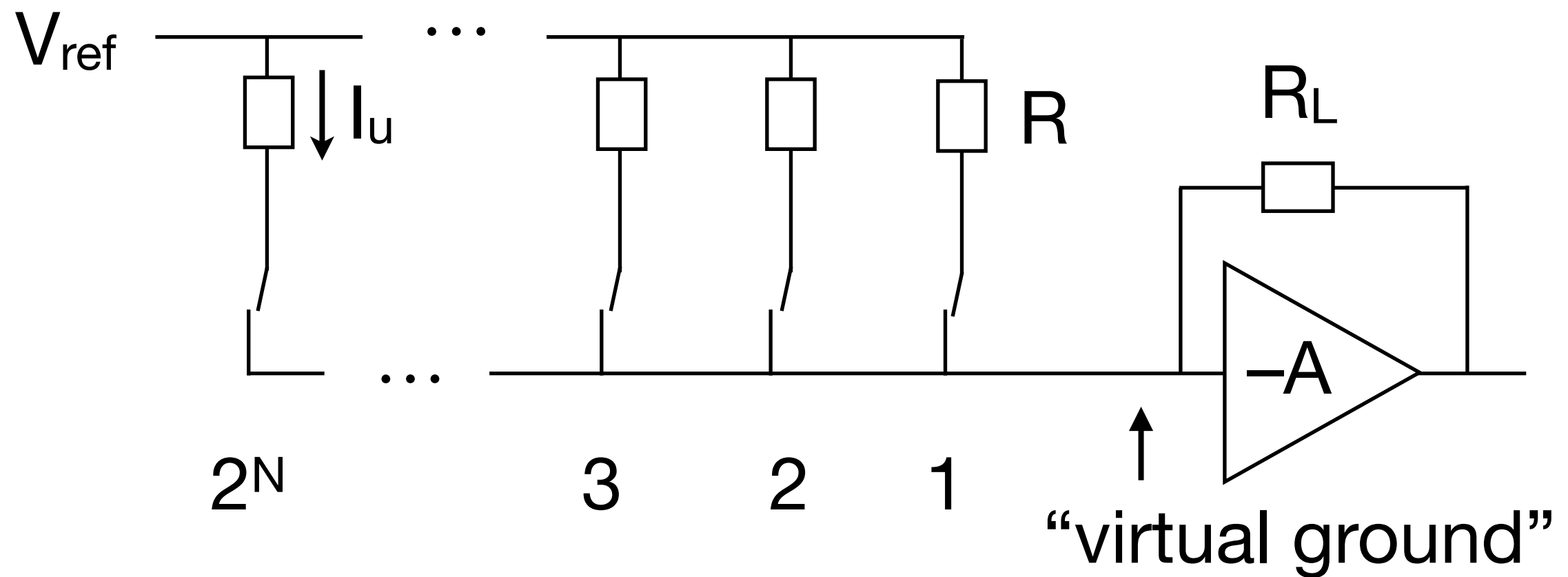
- + Few switches ($\sim N$)
- + Few resistances ($\sim N$)
- + Identical R_i help with matching
- Bad DNL when high-significance bit flips
- Glitches also worse than for Kelvin divider
- Many variations of current-splitting topologies

Binary scaling!

Binary scaling \pm

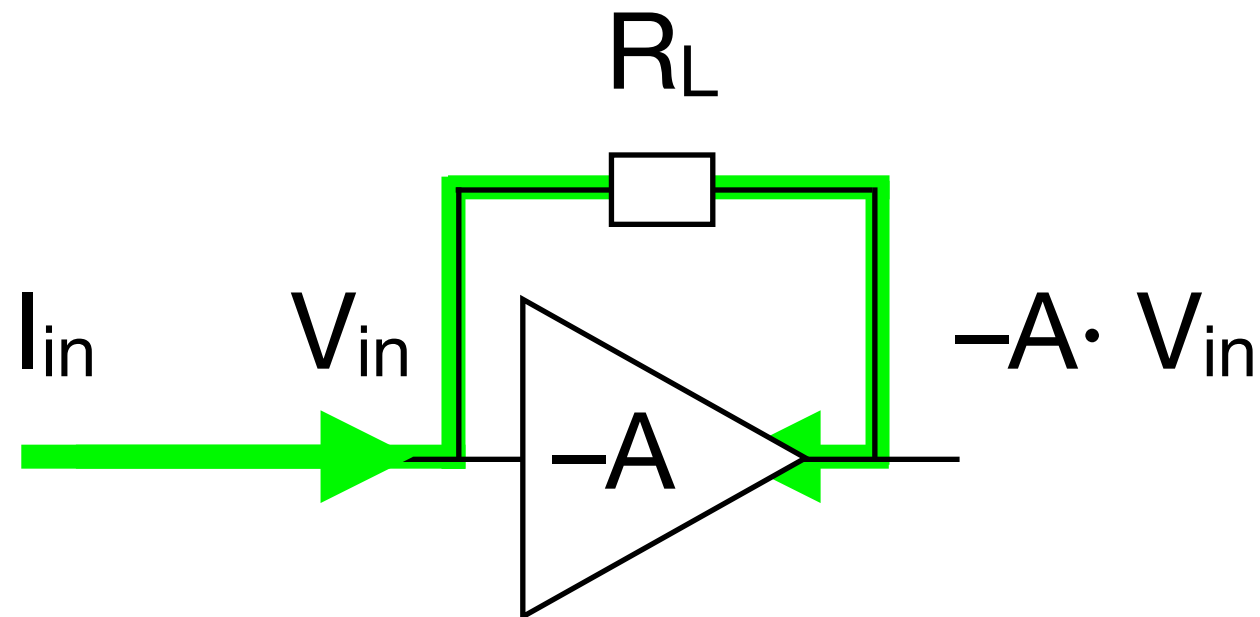
- + Few components ($\sim N$)
- + Less area
 - Less sensitive to gradients
- Bad DNL at MSB transitions
 - More in lab!
- More than ~ 7 bits requires trimmed R_i

Current-summer buffer (unary-scaling case)



$$Z_{\text{in}} \approx 0$$

Buffer input impedance (V_{in} / I_{in})



$$Z_{in} = V_{in} / I_{in}$$

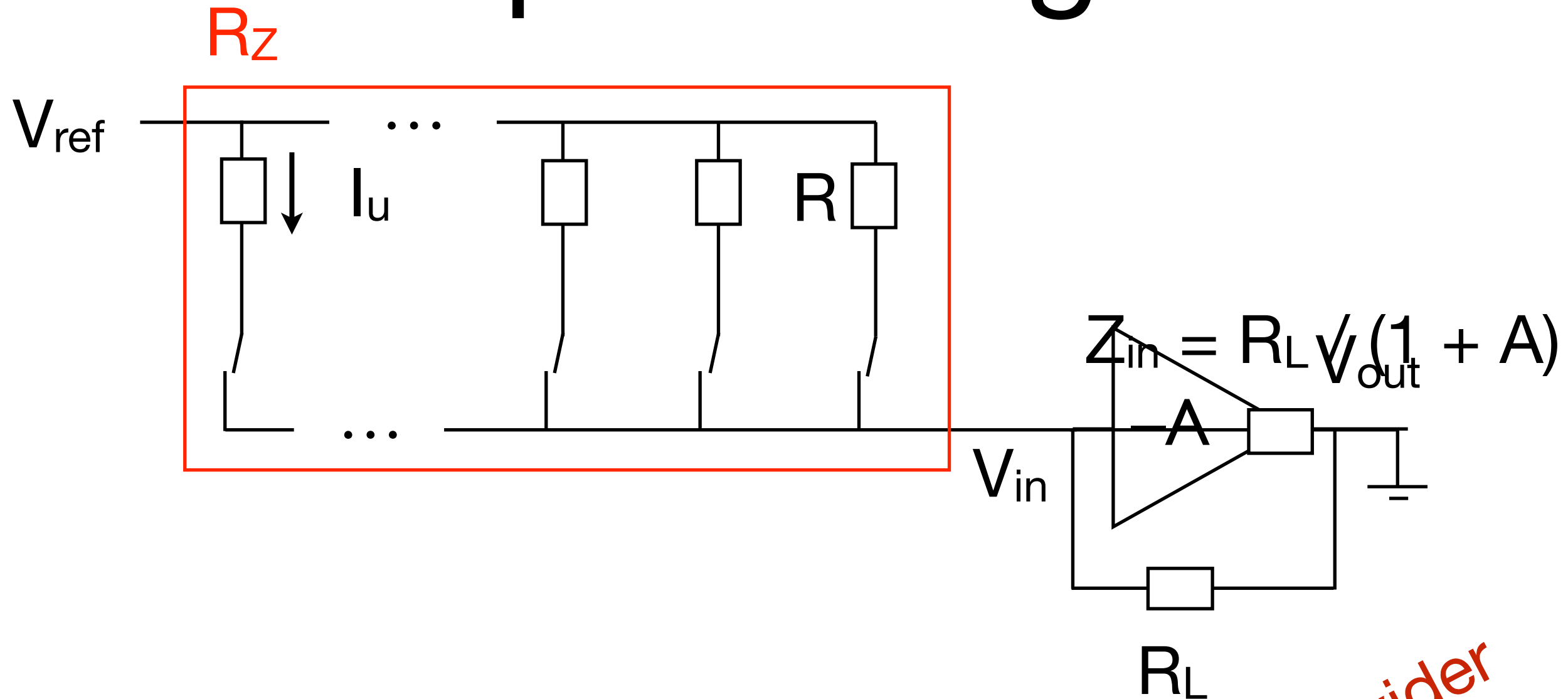
$$I_{in} \cdot R_L = V_{in} \cdot (1 - (-A))$$

$$Z_{in} = V_{in} / I_{in} = R_L / (1 + A)$$

Large A means lower Z_{in}



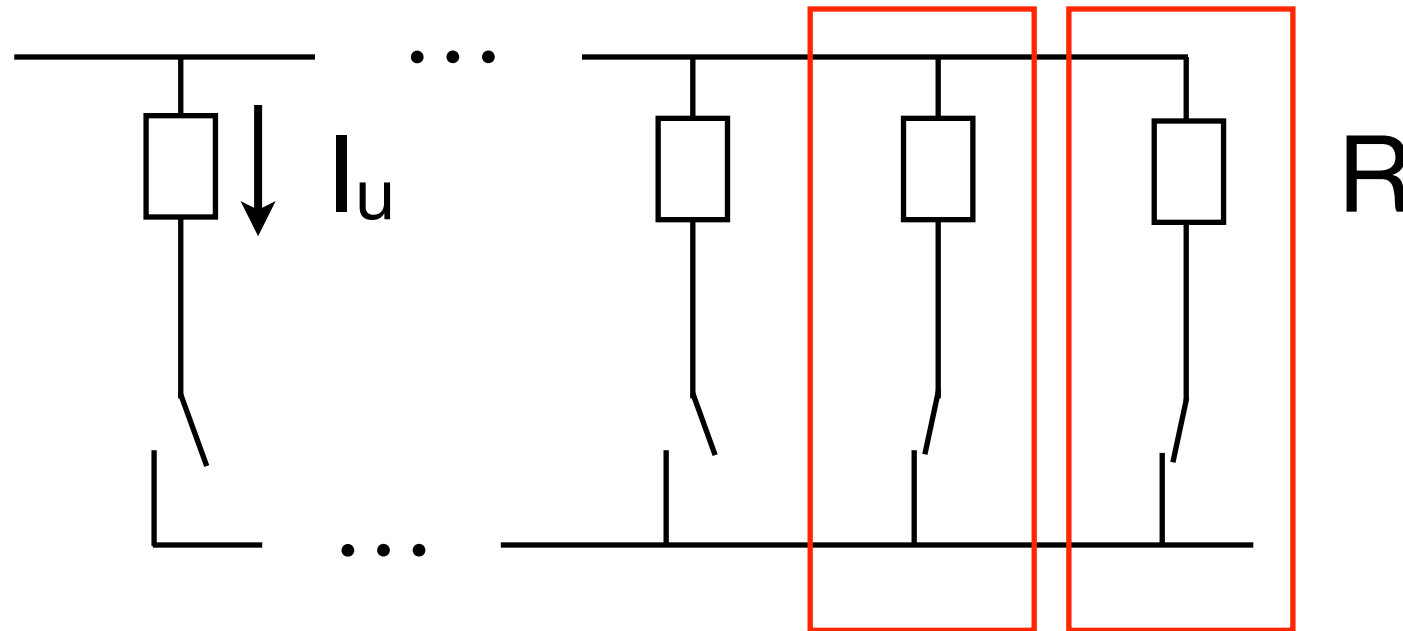
Output voltage



- $V_{out} = -A \cdot V_{in}$
- $V_{in} = V_{ref} \cdot (Z_{in} / (Z_{in} + R_z))$

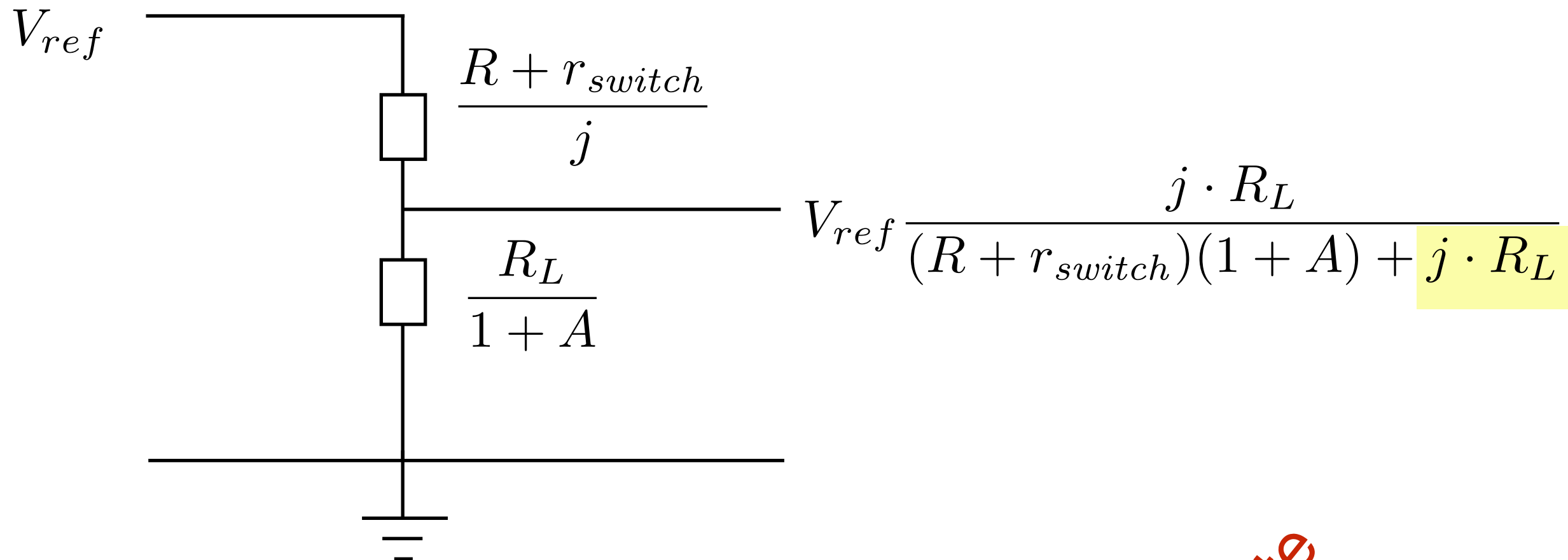
Voltage divider

Impedance of switched R_i



- Each branch: $R + r_{\text{switch}}$ (uniform)
- j connected branches: $(R + r_{\text{switch}}) / j$
- Total impedance depends on j !

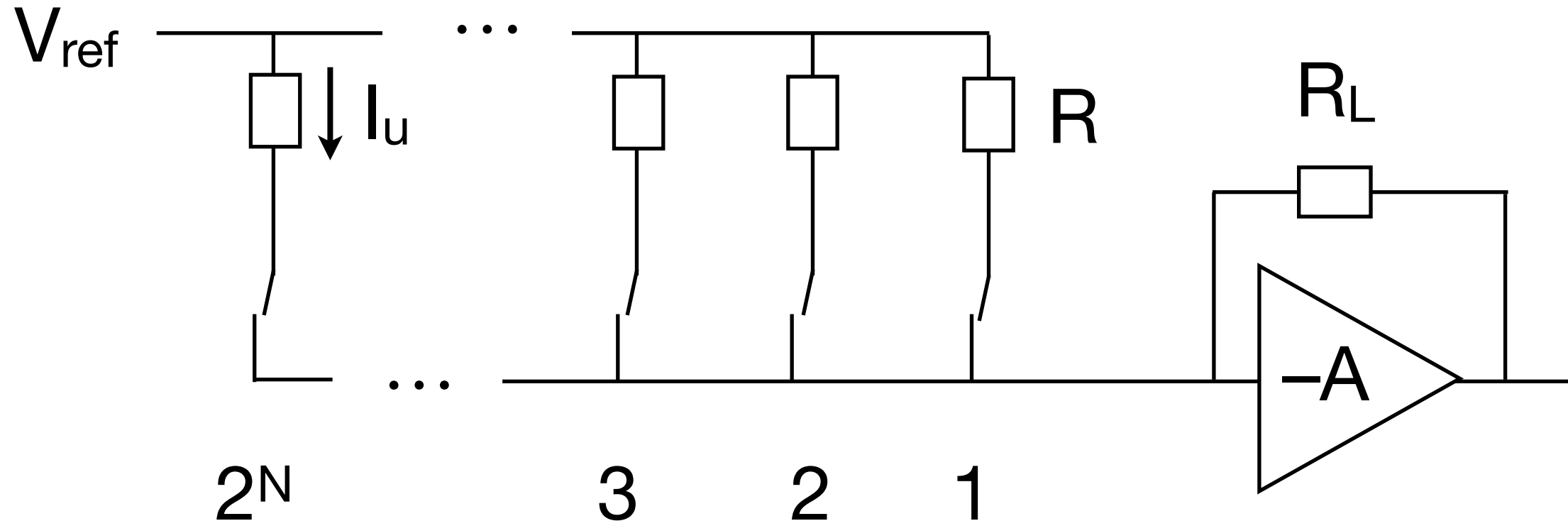
Voltage divider



- Output voltage not linear in j !
- INL! Harmonic distortion!

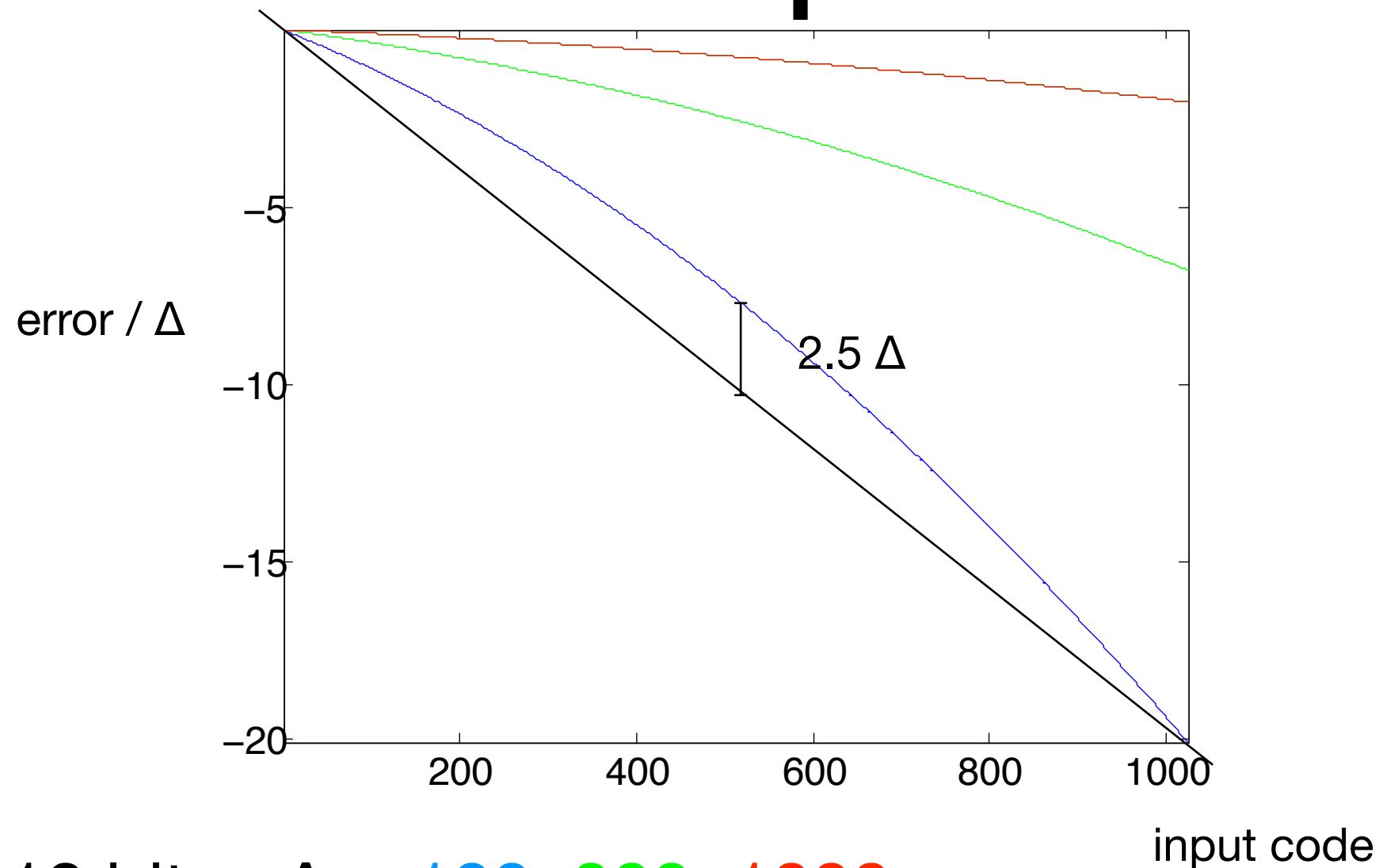
Despite
all-linear
resistors...

How bad is this?



- Assume that $R_L = R / 2^N$
 - Then, output range is approx. V_{ref}
- Calculate error (vs. $-V_{\text{ref}} \cdot j / 2^N$) as function of j

Error plot



- 10 bits, $A = 100, 300, 1000$
- Gain error + nonlinearity (second order)
- Improves with growing A

$$V_{ref} \frac{j \cdot R_L}{(R + r_{switch})(1 + A) + j \cdot R_L}$$

What to do?

- Reduce buffer Z_{in} , i.e., increase A
 - Costs speed and/or power
- Make branch currents less sensitive to Z_{in}
 - Increase branch Z !
 - Devices with gain can be used to change impedances
 - Cf. Z_{in} of buffer!
 - Costs speed, power, complexity...

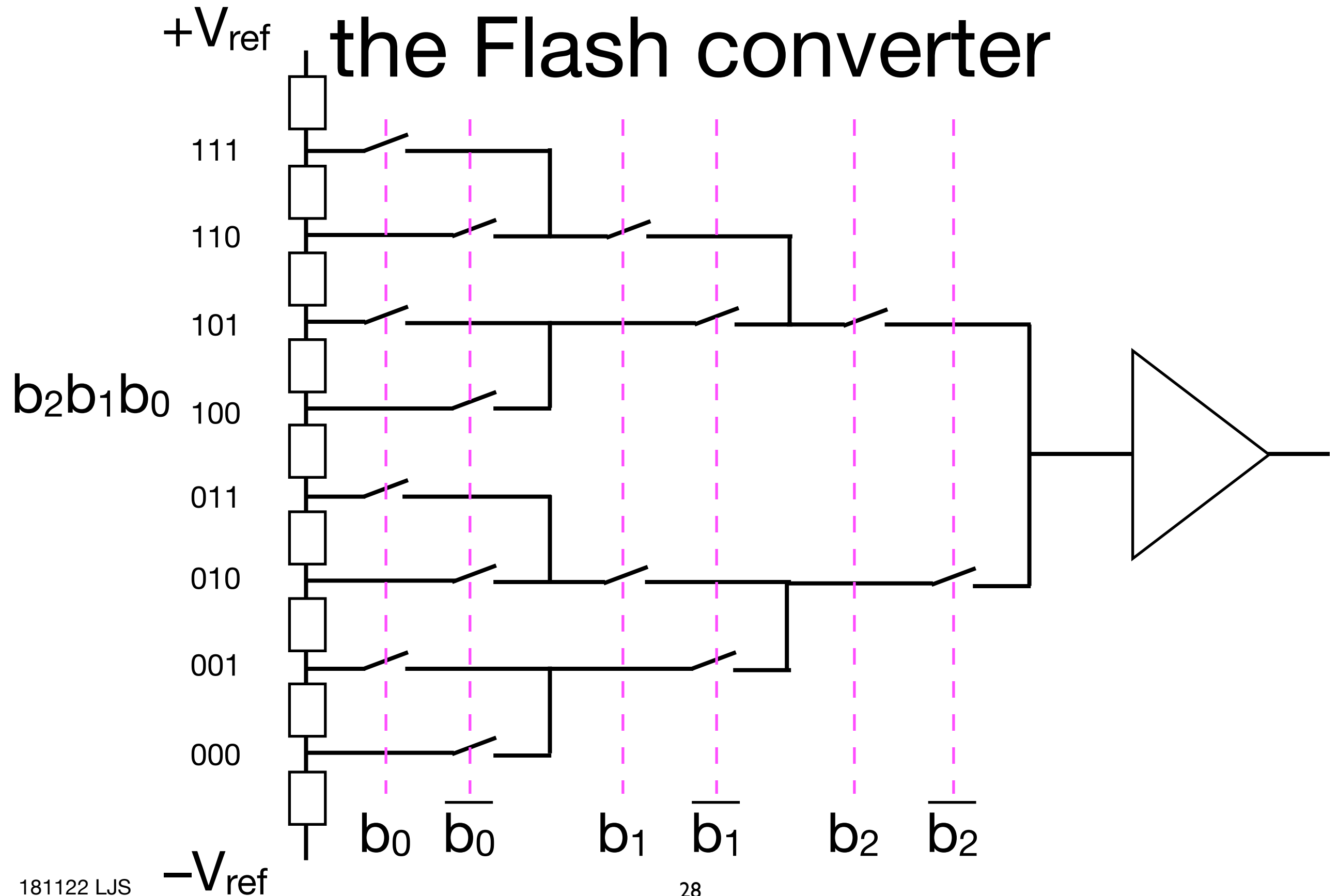
A-to-D conversion

ADC: DAC + compare

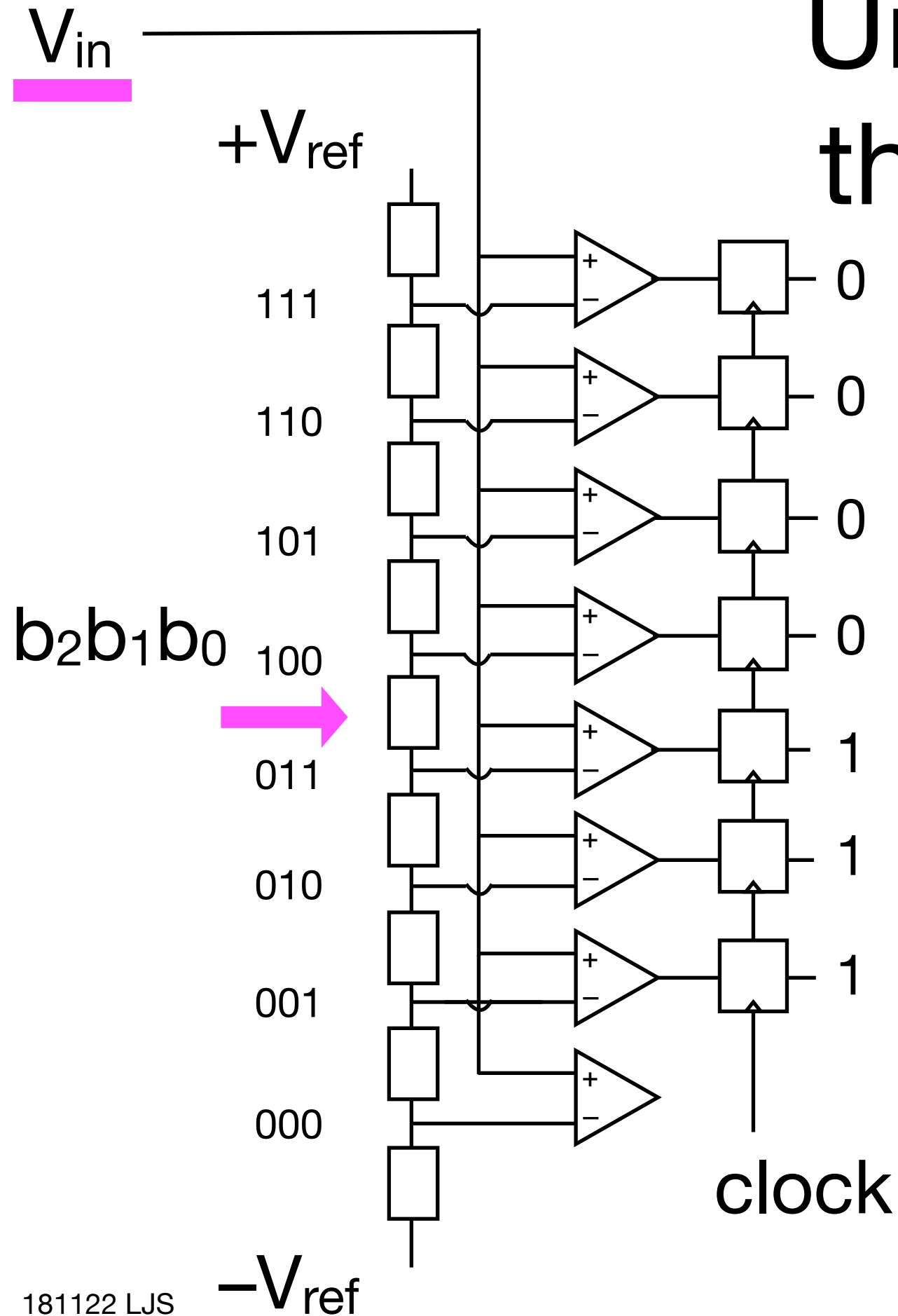
- Typical procedure for A/D conversion:
 - “Guess” a digital value
 - Perform a D/A conversion
 - Compare A/D input with D/A output
 - Adjust if necessary; repeat
- Design decisions:
 - Type of D/A converter
 - How control guess?

Flash converter
Pipelined converter
Successive-approximation
converter

Unary-scaling ADC: the Flash converter



Unary-scaling ADC: the Flash converter

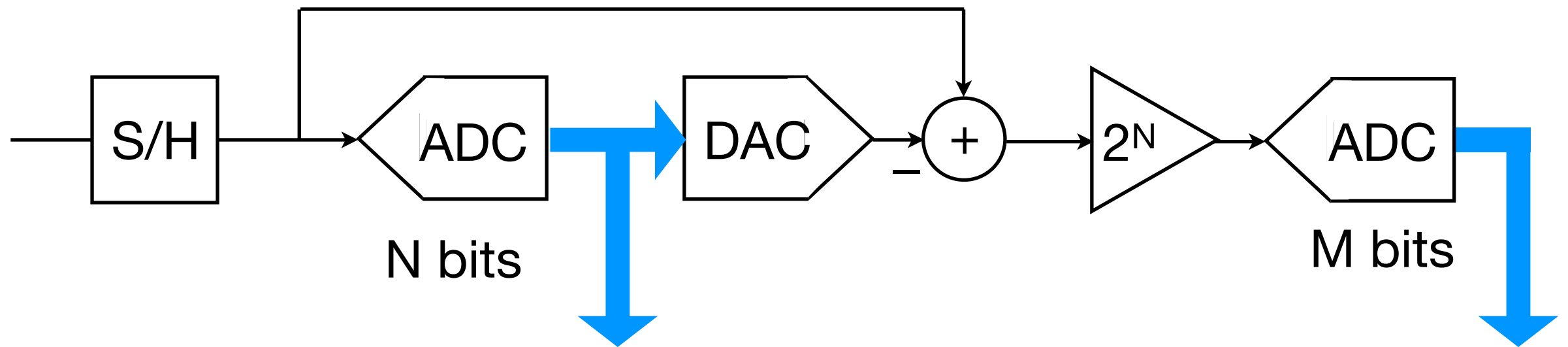


- Compare input with all Kelvin-divider levels in parallel
- Need to re-code digital result: 2^N to N bits
- Cf. thermometer code

Flash ADC properties

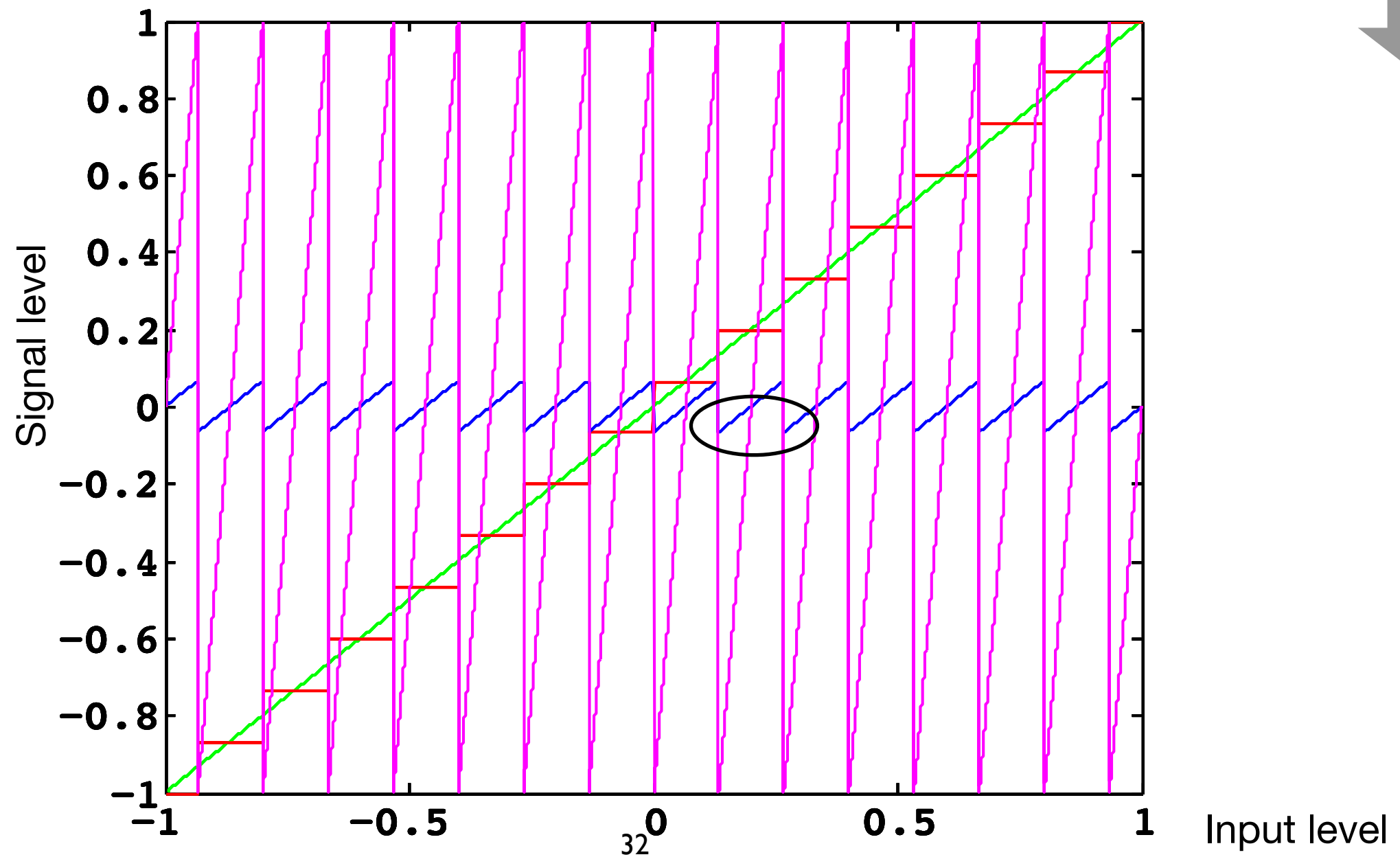
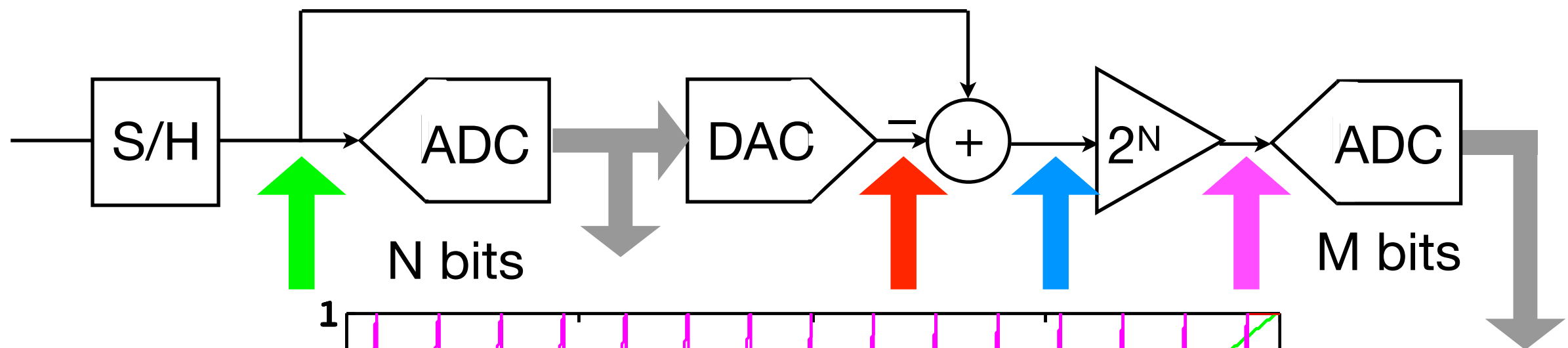
- High speed possible since highly parallel
- Large area since 2^N components
 - Unary scaling!
- High power (2^N components, R string)
- At most ~ 8 bits, several GHz
 - Limits: input signal distribution, clock distribution, power

Subranging converter

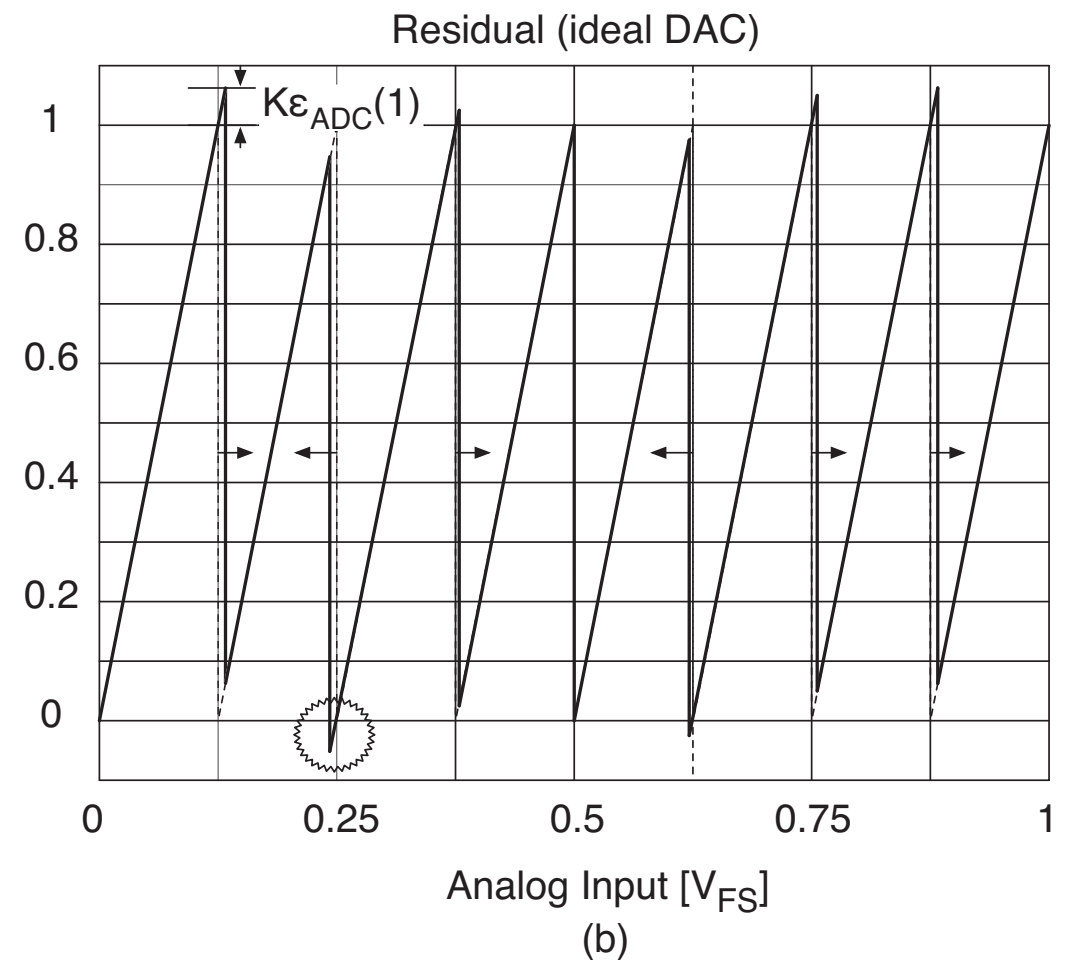
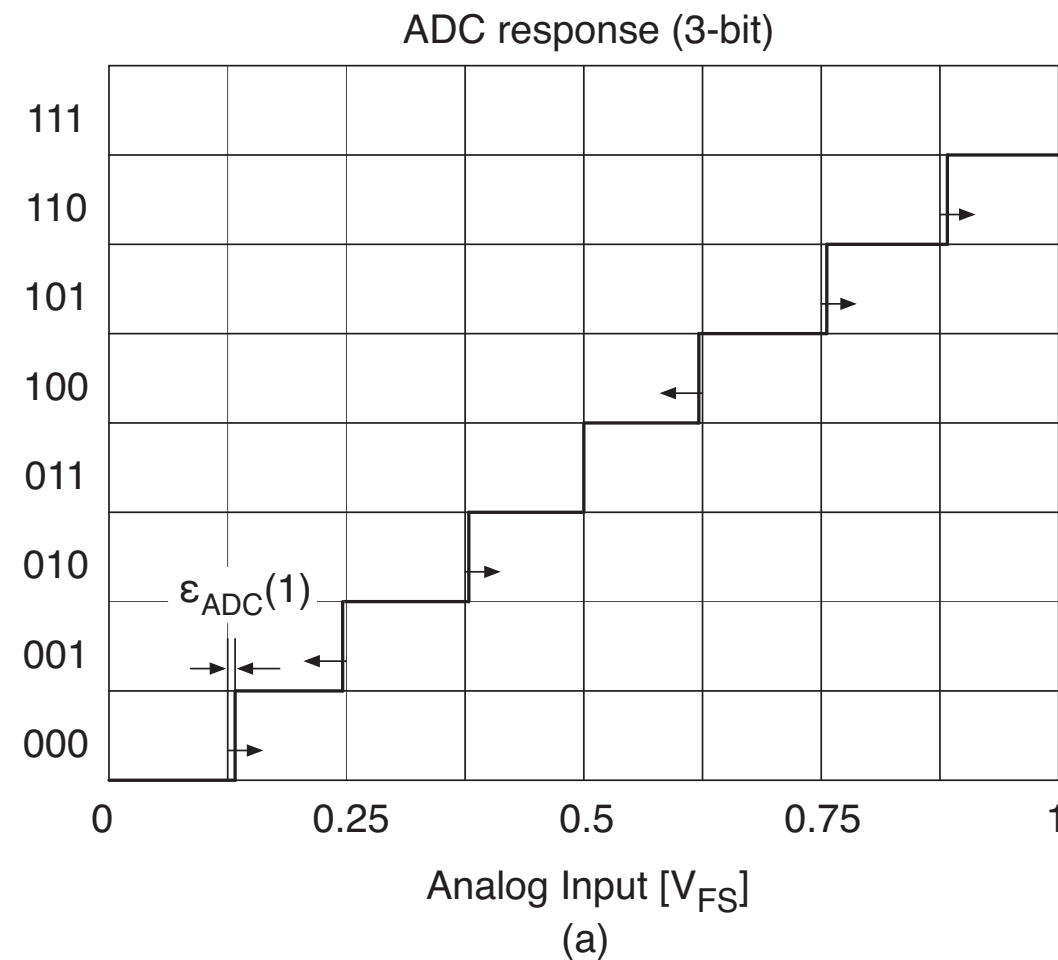


- Two (flash) converters: coarse (N bits) and fine (M bits)
- Total resolution: $N+M$ bits
- Two-stage conversion

Waveforms

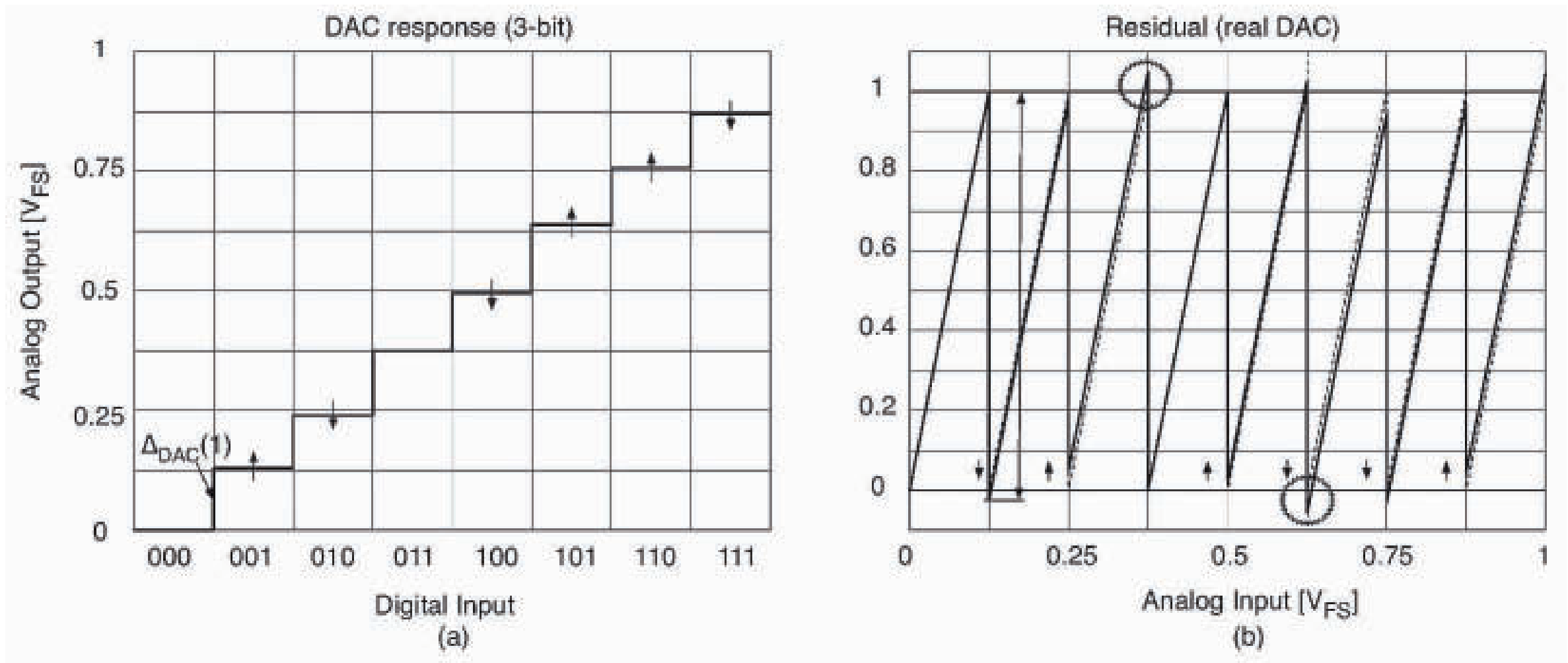


ADC errors



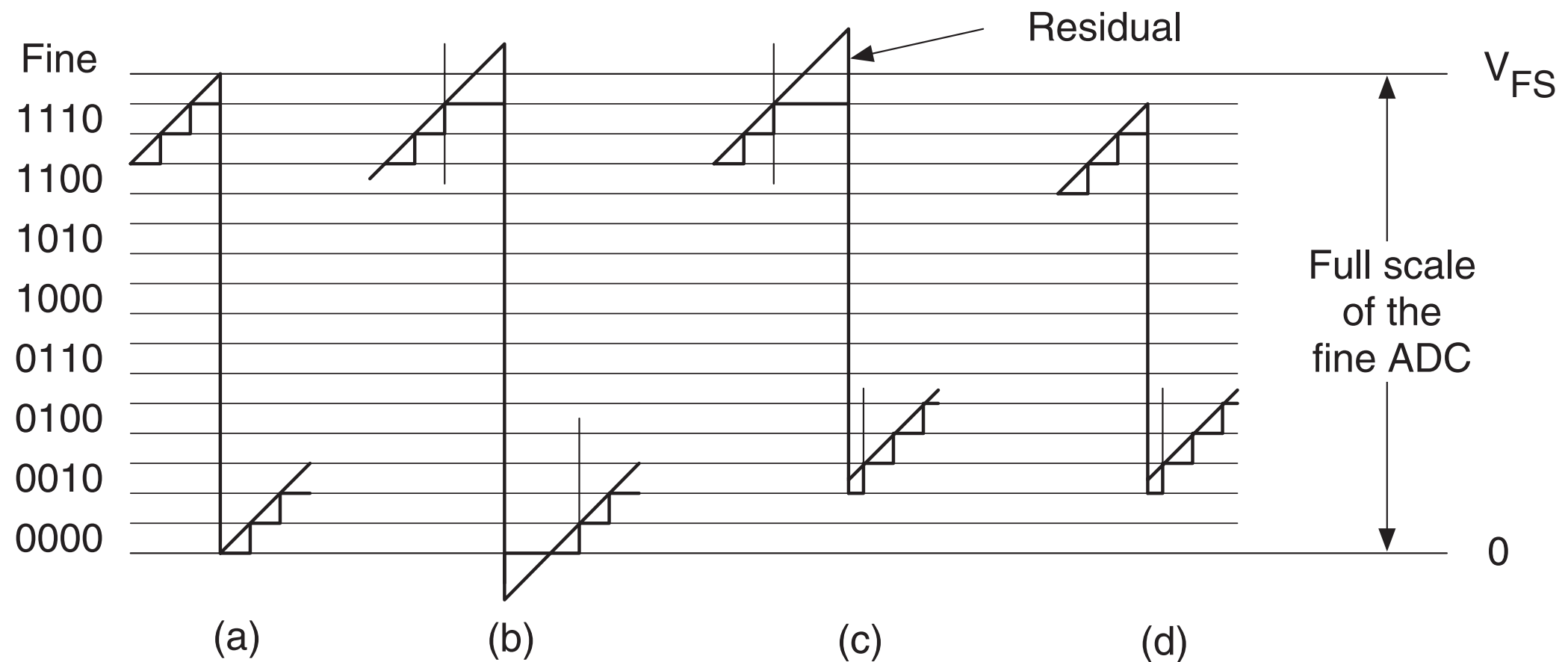
- Vertical lines in residue diagram move sideways

DAC errors



- Angled lines in r.d. move up, down
- Gain errors change slope

Combined errors

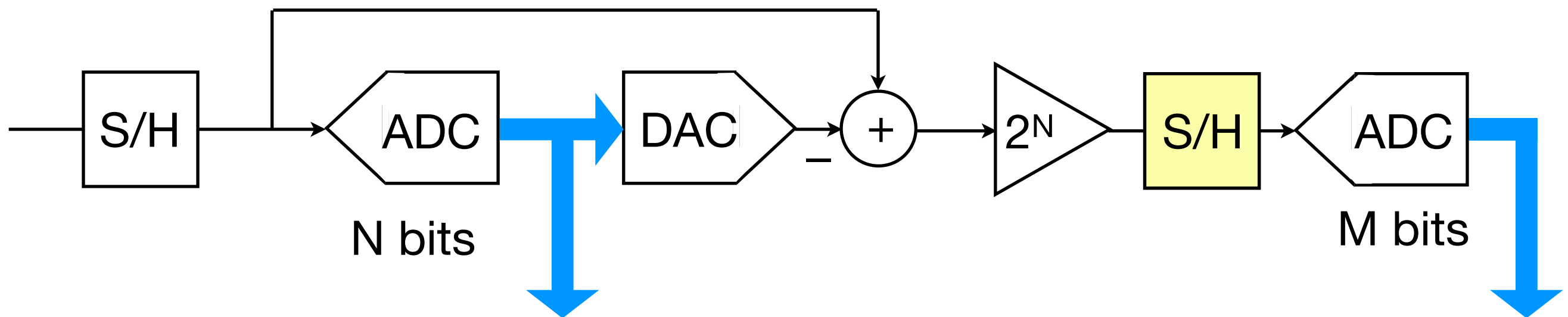


- Missing codes can appear at borders!

Subranging pros + cons

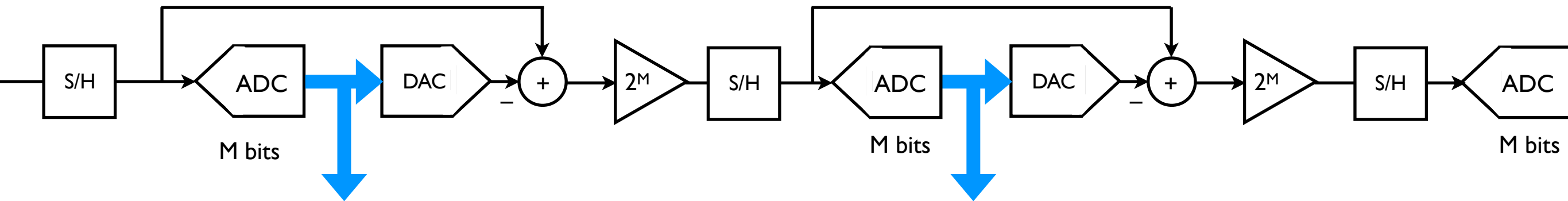
- + Complexity is $2^N + 2^M$ rather than 2^{N+M}
- + Lower-precision first ADC may allow higher speed than one-stage, full-precision ADC
- Increased latency
- High speed requirements at 2nd stage
- 2^N residue amplifier is very critical
 - Missing codes, etc.
 - Can be electronically calibrated (theme 7)

Reduce speed req's



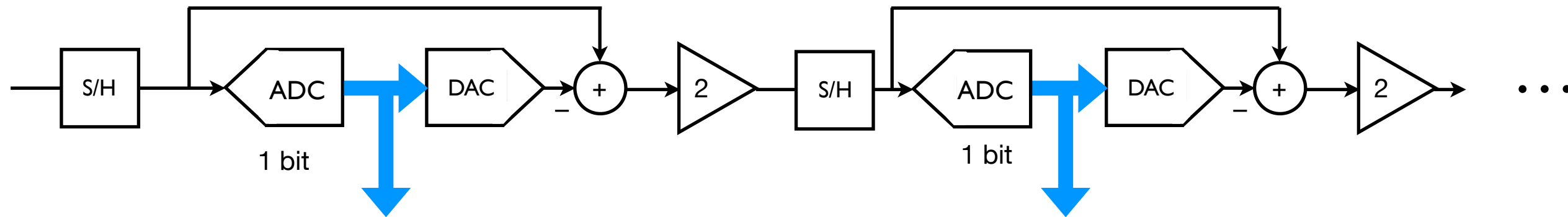
- Pipelining!
- Two samples in process simultaneously
- Need to delay first-stage bits before assembly

Pipelined converter



- Three stages (or more...)
 - How to choose # of stages?
- N-bit total precision, M bits/stage
 - $(N/M) 2^M$ comparators **Grows with M**
 - N/M amplifiers, S/Hs **Shrinks with M**

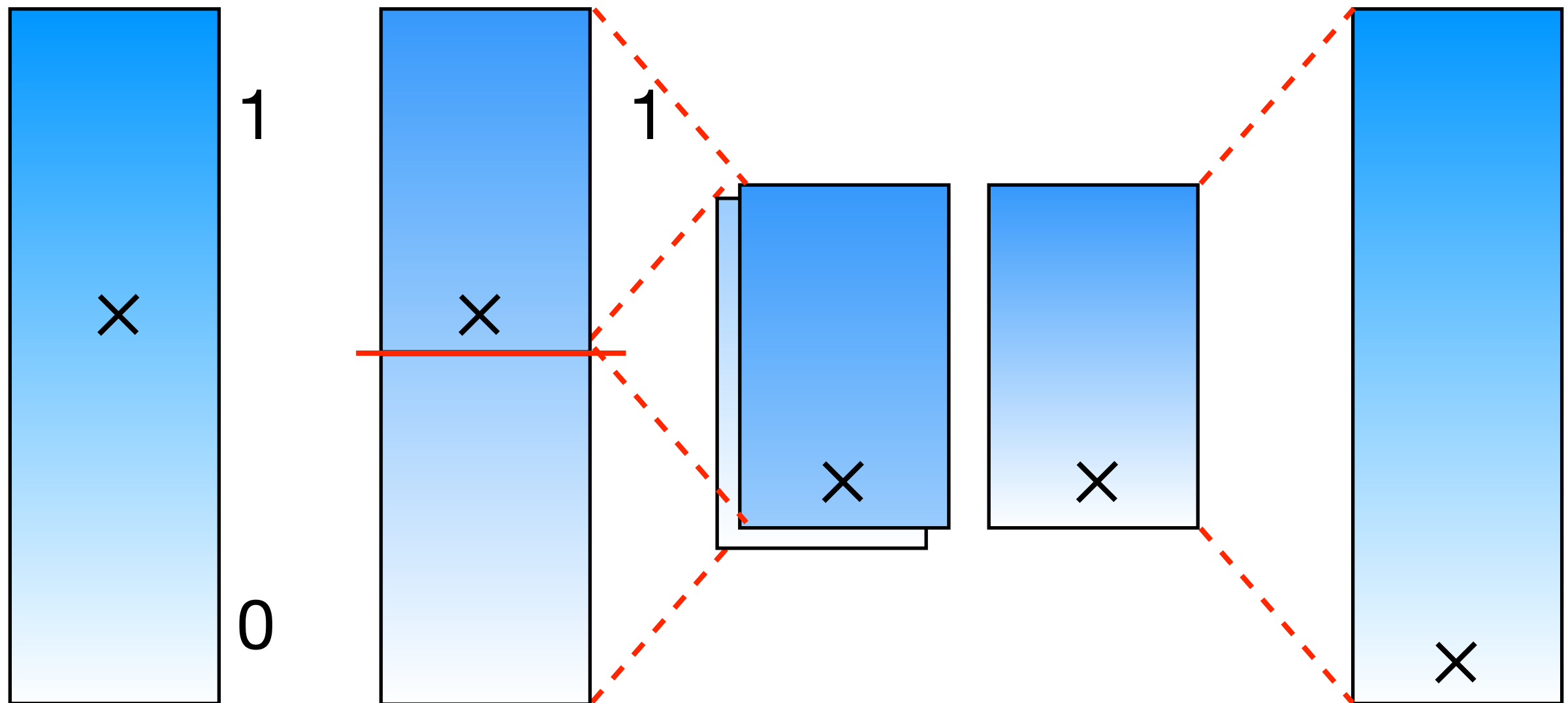
One-bit-per-stage pipeline



- Take the previous design to its logical extreme 😊
- ADC: comparator, DAC: two switches (to $\pm V_{\text{ref}}$)
- Note: no worries about ADC, DAC non-linearity!
- Only gain, offset errors

Stage operation

voltage



compare

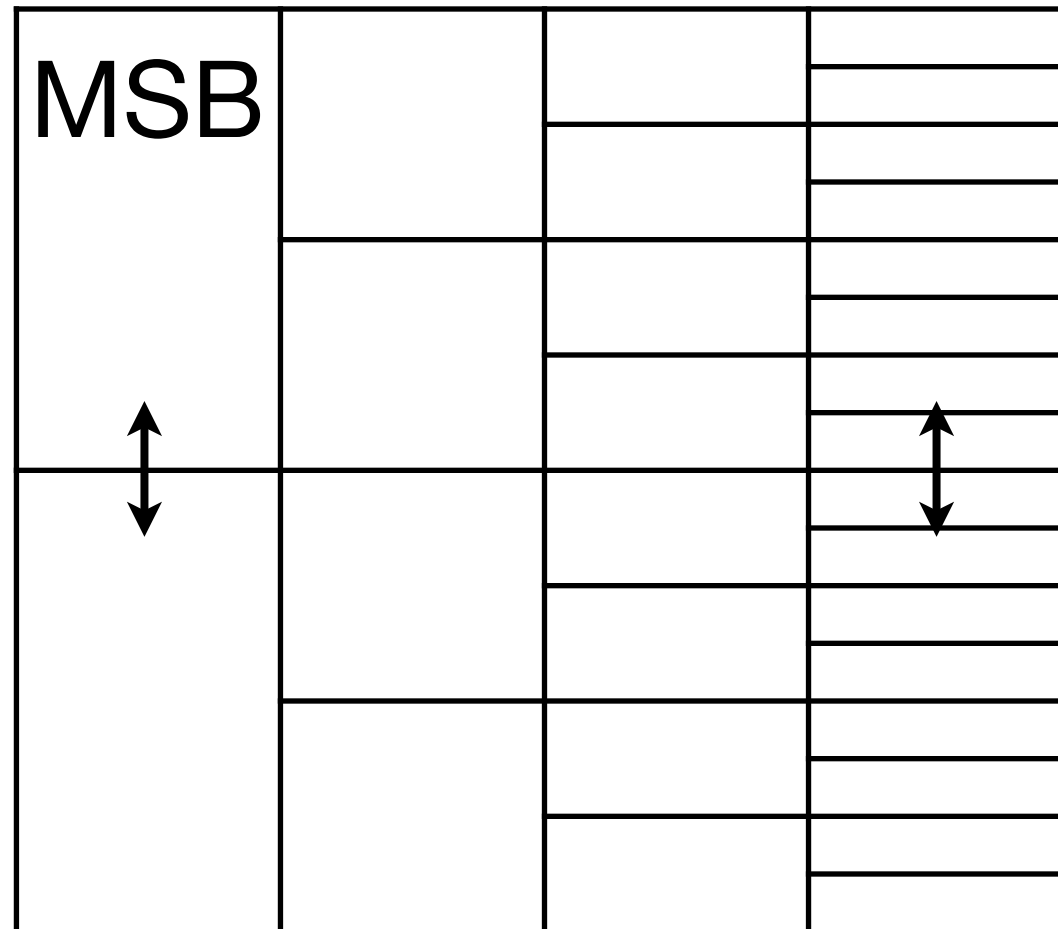
subtract

expand

$\pm 1/4$ of full range

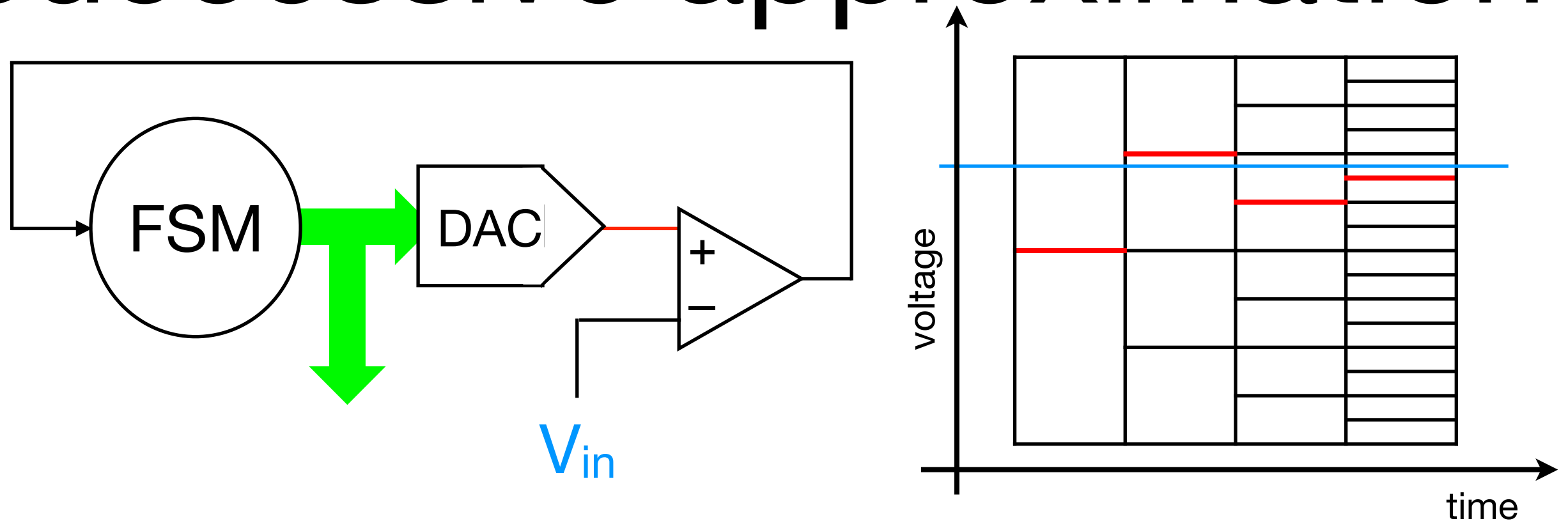
x2

Performance limits



- Comparator offset etc. affects first decision most
 - 1% relative error in MSB means $ENOB < 7$
- Binary scaling!
 - Compare with R-2R DAC!

Successive approximation



- Simple Finite State Machine sets bits in sequence from MSB downwards, depending on previous bits
 - Search by interval halving / bisection
- One full conversion in N cycles
- + No subtractions or other analog processing
- DAC needs to be good to N bits!

Low-power opportunities

Summary

- Converter architecture affects properties
 - Reachable resolution
 - Maximum speed
 - Power dissipation
 - ...
- Two major classes: unary vs. binary scaling
 - Differ in error characteristics